

F2: Smart Design - Ergonomics



The F2 is a new concept of 20-200kV TEM equipped with a Cold FEG. This new generation of multi-purpose electron microscope is designed specifically to meet today's diversified needs.

Thanks to the high brightness and small probe size of the Cold FEG, the F2 is able to reach an unprecedented guaranteed resolution for STEM (0.14nm), EDS (1.7sr) and EELS (0.3eV) at the same time; creating a new class of high-end non-corrected TEM

The F2 has been designed to fulfil the user's requirements while maintaining an incredible ease of use.

The F2 incorporates a new, intuitive user interface specifically designed for analytical electron microscopy. This new interface integrates many improvements for the TEM control, such as; automatic functions (auto brightness/contrast, auto focus, auto Z, auto stigmator), coma free auto alignment and off-line data processing (Analysis Center). The software can be tuned at your convenience to provide you with the best working environment.

To facilitate the use of the F2, a new automated sample holder transfer system, the SpecPorter, has been developed to load samples. Once loaded, the PicoStage conducts precise, high speed sample movements of 0.2 nm steps, allowing the operator to move the field of view smoothly over a wide spatial scale range from millimeters to picometers.

The F2 has been developed as a next-generation electron microscope with high performance and ease of use.



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